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Application No.: 10/656,006

Docket No.: JCLA11225

AMENDMENT

IN THE CLAIMS

Please amend claims as follows:

Claims 1-7. (canceled)

Claim 8. (currently amended) A DVD ROM chipset testing board for undergoing

high temperature operating life testing to a DVD ROM chipset, the DVD ROM chipset

testing board comprises: a testing base, having at least one chipset socket for plugging the

DVD ROM chipset, and a connector for coupling to a testing device of the DVD ROM

chipset, wherein the testing device provides a digital input signal varied with a frequency;

and a phase-shift RF-signal generating circuit, according to the digital input signal, for

generating a first phase-shift RF signal, a second phase-shift RF signal, a third phase-shift

RF signal, and a fourth phase-shift RF signal for testing an analog circuit of the DVD

ROM chipset, wherein the first phase-shift RF signal and the second phase-shift RF

signal are in phase, and are differed by a phase shift from the third phase-shift RF signal

and the fourth phase-shift RF signal.

Claim 9. (previously presented) The DVD ROM chipset testing board as recited in

claim 8, wherein the phase-shift RF signal generating circuit comprises: a first signal

potential divider, wherein the digital input signal is received, voltage divided, and output;

a first high pass filter, coupling to the first signal potential divider, wherein the dc

composition of the digital input signal that is voltage divided is eliminated in order to

generate the first phase-shift RF signal; a second high pass filter, coupling to the first

signal potential divider, wherein the dc composition of the digital input signal that is

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voltage divided is eliminated in order to generate the second phase-shift RF signal; a

phase shifter, wherein the digital input signal is received, shifted by a phase and output; a

second signal potential divider, coupling to the phase-shifter, wherein the digital input

signal that is phase shifted is received, voltage divided, and output; a third high pass filter,

coupling to the second signal potential divider, wherein the dc composition of the digital

input signal that is phase shifted and voltage divided is eliminated in order to generate the

third phase-shift RF signal; and a fourth high pass filter, coupling to the second signal

potential divider, wherein the dc composition of the digital input signal that is phase

shifted and voltage divided is eliminated in order to generate the fourth phase-shift RF

signal.

Claim 10. (previously presented) The DVD ROM chipset testing board as recited

in claim 9, wherein each of the first signal potential divider and the second signal

potential divider comprises two resistors in series.

Claim 11. (previously presented) The DVD ROM chipset testing board as recited

in claim 9, wherein each of the first high pass filter, the second high pass filter, the third

high pass filter, and the fourth high pass filter comprises a capacitor.

Claim 12. (previously presented) The DVD ROM chipset testing board as recited

in claim 9 wherein the phase shifter comprises: an operating amplifier, comprising a

positive input terminal, a negative input terminal, and an output terminal, wherein the

output terminal is to output the digital input signal that is phase shifted; a first resistor,

wherein one end of the first resistor couples to the digital input signal, and the other end

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couples to the positive input terminal; a capacitor, wherein one end of the capacitor

couples to the positive input terminal, and the other end is grounded; a second resistor,

wherein one end of the second resistor couples to the digital input signal, and the other

end couples to the negative input terminal; and a third resistor, wherein one end of the

third resistor couples to the negative input terminal and the other end coupes to the output

terminal.

Claim 13. (previously presented) The DVD ROM chipset testing board as recited

in claim 12, wherein the second resistor and the third resistor have identical resistance.

Claim 14. (previously presented) The DVD ROM chipset testing board as recited

in claim 9, wherein the phase shifter possesses voltage gain of 1, and phase shift of

40.degree.

Claim 15. (previously presented) The DVD ROM chipset testing board as recited

in claim 9, wherein the first phase-shift RF signal, the second phase-shift RF signal, the

third phase-shift RF signal, and the fourth phase-shift RF signal have peak-to-peak value

of 75 mV and frequency of 5 MHz.

Claims 16-18. (canceled)

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